

UNISONIC TECHNOLOGIES CO., LTD

11N50-CB Preliminary Power MOSFET

11A, 500V N-CHANNEL POWER MOSFET

■ DESCRIPTION

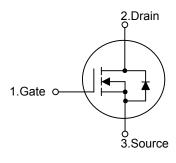
The **UTC 11N50-CB** is an N-channel enhancement mode power MOSFET. It uses UTC advanced planar stripe, DMOS technology to provide customers perfect switching performance, minimal on-state resistance. It also can withstand high energy pulse in the avalanche and commutation mode.

The **UTC 11N50-CB** is universally applied in electronic lamp ballasts based on half bridge topology, high efficiency switched mode power supplies, active power factor correction, etc.

■ FEATURES

- * $R_{DS(ON)}$ < 0.55 Ω @ V_{GS} = 10 V, I_{D} = 5.5 A
- * Fast Switching
- * With 100% Avalanche Tested

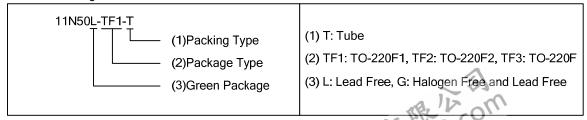
■ SYMBOL



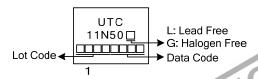
■ ORDERING INFORMATION

Ordering Number		Dackago	Pin Assignment			Dacking	
Lead Free	Halogen Free	Package	1	2	3	Packing	
11N50L-TF1-T	11N50G-TF1-T	TO-220F1	G	D	S	Tube	
11N50L-TF2-T	11N50G-TF2-T	TO-220F2	G	D	S	Tube	
11N50L-TF3-T	11N50G-TF3-T	TO-220F	G	D	S	Tube	

Note: Pin Assignment: G: Gate D: Drain S: Source



■ MARKING



TO-220F1

TO-220F1

TO-220F2

<u>www.unisonic.com.tw</u> 1 of 5

ABSOLUTE MAXIMUM RATINGS (T_C =25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	500	V
Gate-Source Voltage		V_{GSS}	±30	V
Drain Current	Continuous	I _D	11	Α
	Pulsed (Note 2)	I _{DM}	44	Α
Avalanche Current (Note 2)		I _{AR}	4.5	Α
Avalanche Energy	Single Pulsed (Note 3)	E _{AS}	101	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	3.9	V/ns
Power Dissipation		P _D	48	W
Junction Temperature		TJ	150	°C
Storage Temperature Range		T _{STG}	-55 ~ +150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3. L=10mH, I_{AS} =4.5A, V_{DD} = 50V, R_{G} =25 Ω , Starting T_{J} =25 $^{\circ}$ C
- 4. $I_{SD} \le 11A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$

THERMAL DATA

PARAMETER	SYMBOL	RATING	UNIT	
Junction to Ambient	θ_{JA}	62.5	°C/W	
Junction to Case	$\theta_{ m JC}$	2.6	°C/W	

ELECTRICAL CHARACTERISTICS (T_J =25°C, unless otherwise specified)

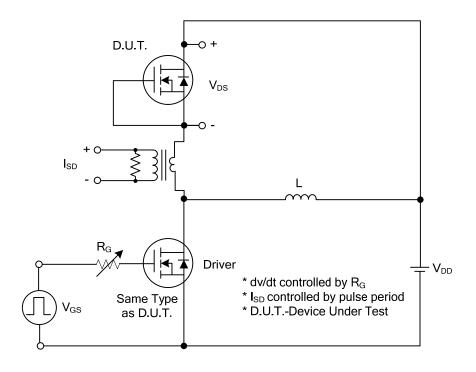
PARAMETER		SYMBOL	TEST CONDITIONS MIN		TYP	MAX	UNIT	
OFF CHARACTERISTICS								
Drain-Source Breakdown Voltage		BV_{DSS}	V _{GS} =0V, I _D =250μA 5				V	
Drain-Source Leakage Current		I_{DSS}	V _{DS} =500V, V _{GS} =0V			10	μΑ	
Gate-Source Leakage Current	Forward	- I _{GSS}	V_{DS} =0 V , V_{GS} =±30 V			±100	nA	
	Reverse		V_{GS} =-30V, V_{DS} =0V			-100	nA	
ON CHARACTERISTICS								
Gate Threshold Voltage		$V_{GS(TH)}$	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$			4.0	V	
Drain-Source On-State Resistance		R _{DS(ON)}	V _{GS} =10V, I _D =5.5A			0.55	Ω	
DYNAMIC PARAMETERS								
Input Capacitance	nput Capacitance				1690		рF	
Output Capacitance		Coss	V _{GS} =0V,V _{DS} =25V, f=1.0MHz		150		рF	
Reverse Transfer Capacitance		C _{RSS}			130		рF	
SWITCHING PARAMETERS								
Total Gate Charge (Note 1)		Q_{G}	V _{DS} =50V, V _{GS} =10V, I _D =1.3A ,		37		nC	
Gate to Source Charge		Q_GS	I _G =100μA (Note 1, 2)		6		nC	
Gate to Drain Charge		Q_GD	IG-100μΑ (Note 1, 2)		7		nC	
Turn-ON Delay Time (Note 1)		$t_{D(ON)}$	V _{DD} =30V, V _{GS} =10V, I _D =0.5A, R _G =25Ω (Note 1, 2)		73		ns	
Rise Time		t_R			45		ns	
urn-OFF Delay Time		$t_{D(OFF)}$			250		ns	
Fall-Time		t _F			50		ns	
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS								
Maximum Body-Diode Continuous Current		Is	a 12 -	2		11	Α	
Maximum Body-Diode Pulsed Current		I _{SM}	K BE CO			44	Α	
Drain-Source Diode Forward Voltage (Note 1)		V_{SD}	I _S =11A, V _{GS} =0V			1.4	V	
Body Diode Reverse Recovery Time (Note 1)		t _{rr}	I _S =11A, V _{GS} =0V,		310		ns	
Body Diode Reverse Recovery Charge		Qrr	dl⊧/dt=100A/µs		2.23		μC	

Notes: 1. Pulse Test : Pulse width ≤ 300µs, Duty cycle ≤ 2%.

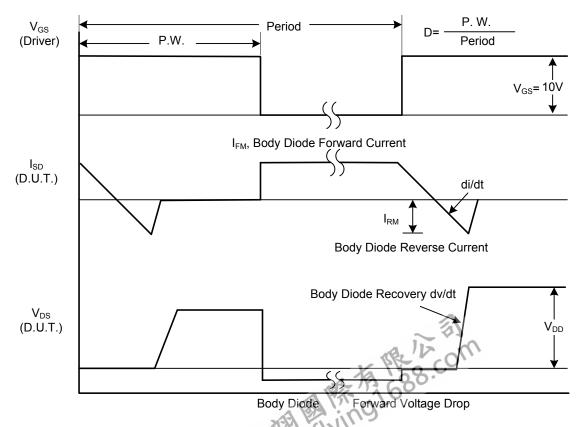
2. Essentially independent of operating temperature.



TEST CIRCUITS AND WAVEFORMS

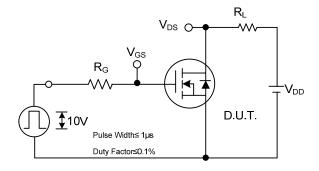


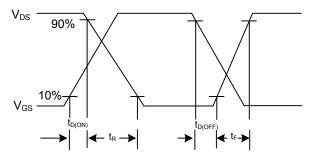
Peak Diode Recovery dv/dt Test Circuit



Peak Diode Recovery dv/dt Waveforms

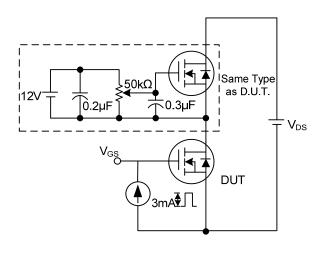
TEST CIRCUITS AND WAVEFORMS (Cont.)

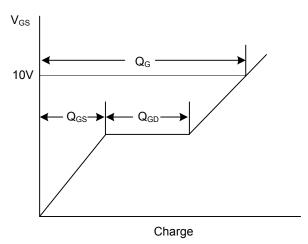




Switching Test Circuit

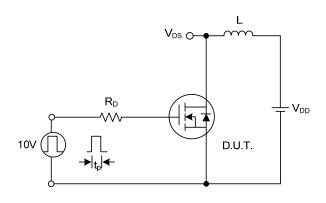
Switching Waveforms

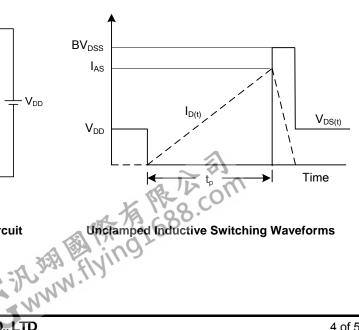




Gate Charge Test Circuit

Gate Charge Waveform





Unclamped Inductive Switching Test Circuit

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